

INTERNATIONAL STANDARD

**High frequency inductive components – Electrical characteristics and measuring methods –
Part 1: Nanohenry range chip inductor**





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INTERNATIONAL ELECTROTECHNICAL COMMISSION

HIGH FREQUENCY INDUCTIVE COMPONENTS – ELECTRICAL CHARACTERISTICS AND MEASURING METHODS –

Part 1: Nanohenry range chip inductor

FOREWORD

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International Standard IEC 62024-1 has been prepared by IEC technical committee 51: Magnetic components, ferrite and magnetic powder materials.

This third edition cancels and replaces the second edition published in 2008. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) addition of voltage-drop method of DC resistance measuring;
- b) unification of technical terms.

The text of this International Standard is based on the following documents:

CDV	Report on voting
51/1187/CDV	51/1202/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 62024 series, published under the general title *High frequency inductive components – Electrical characteristics and measuring methods*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

HIGH FREQUENCY INDUCTIVE COMPONENTS – ELECTRICAL CHARACTERISTICS AND MEASURING METHODS –

Part 1: Nanohenry range chip inductor

1 Scope

This part of IEC 62024 specifies electrical characteristics and measuring methods for the nanohenry range chip inductor that is normally used in high frequency (over 100 kHz) range.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61249-2-7, *Materials for printed boards and other interconnecting structures – Part 2-7: Reinforced base materials clad and unclad – Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test) copper-clad*

IEC 62025-1, *High frequency inductive components – Non-electrical characteristics and measuring methods – Part 1: Fixed, surface mounted inductors for use in electronic and telecommunication equipment*

ISO 6353-3, *Reagents for chemical analysis – Part 3: Specifications – Second series*

ISO 9453, *Soft solder alloys – Chemical compositions and forms*

3 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

4 Inductance, Q-factor and impedance

4.1 Inductance

4.1.1 Measuring method

The inductance of an inductor is measured by the vector voltage/current method.

4.1.2 Measuring circuit

An example of the circuit for the vector voltage/current method is shown in Figure 1.